

# STL120N4F6AG

# Automotive-grade N-channel 40 V, 2.9 mΩ typ., 55 A STripFET™ F6 Power MOSFET in a PowerFLAT™ 5x6 package

Datasheet - production data

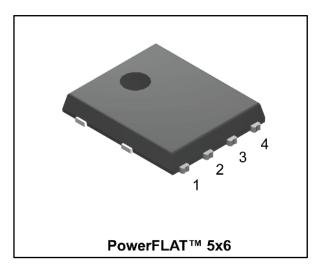
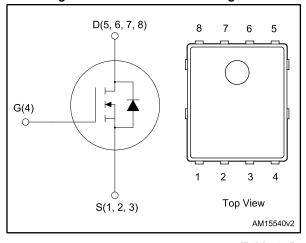


Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD
STL120N4F6AG	40 V	3.6 mΩ	55 A



- AEC-Q101 qualified
- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss
- Wettable flank package

### **Applications**

Switching applications

### **Description**

This device is an N-channel Power MOSFET developed using the STripFET™ F6 technology with a new trench gate structure. The resulting Power MOSFET exhibits very low R<sub>DS(on)</sub> in all packages.

**Table 1: Device summary** 

Order code	Marking	Package	Packaging
STL120N4F6AG	120N4F6	PowerFLAT™ 5x6	Tape and reel

Contents STL120N4F6AG

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STL120N4F6AG Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>G</sub> s	Gate-source voltage	±20	V
$V_{DS}$	Drain-source voltage	40	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	55	Α
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	55	Α
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	220	Α
Ртот	Total dissipation at T <sub>C</sub> = 25 °C	115	W
T <sub>stg</sub>	Storage temperature range	EE to 17E	°C
Tj	Operating junction temperature range	-55 to 175	°C

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	1.3	۰۵۸۸
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb	31.3	°C/W

#### Notes:

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
lav	Avalanche current, repetitive or not repetitive (pulse width limited by maximum junction temperature)	20	А
Eas	Single pulse avalanche energy $(T_j = 25  ^{\circ}C,  I_C = I_{AV},  V_{DD} = 25  V)$	200	mJ

 $<sup>^{(1)}</sup>$ Drain current is limited by package, the current capability of the silicon is 120 A at 25  $^{\circ}$ C.

<sup>&</sup>lt;sup>(2)</sup>Pulse width is limited by safe operating area.

 $<sup>^{(1)}</sup>$ When mounted on 1 inch² 2 Oz. Cu board, t  $\leq$  10 s

Electrical characteristics STL120N4F6AG

### 2 Electrical characteristics

(T<sub>C</sub>= 25 °C unless otherwise specified)

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
	Zoro goto voltago droin	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V}$			1	μΑ
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V},$ Tj = 125 °C <sup>(1)</sup>			10	μΑ
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2		4	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 13 A		2.9	3.6	mΩ

#### Notes:

**Table 6: Dynamic** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		ı	3700	1	pF
Coss	Output capacitance	$V_{DS}$ = 25 V, f = 1 MHz,	-	625	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	V <sub>GS</sub> = 0 V		295	1	pF
$Q_g$	Total gate charge $V_{DD} = 20 \text{ V}, I_D = 26 \text{ A},$		-	63	-	nC
Qgs	Gate-source charge	Gate-source charge V <sub>GS</sub> = 0 to 10 V (see <i>Figure 14: "Test circuit for</i>		19	-	nC
Q <sub>gd</sub>	Gate-drain charge	gate charge behavior")	-	15	1	nC
Rg	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	1.5	-	Ω

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 20 \text{ V}, I_D = 13 \text{ A},$	-	20	-	ns
tr	Rise time	R <sub>G</sub> = 4.7 $\Omega$ , V <sub>GS</sub> = 10 V (see Figure 13: "Test circuit for	-	70	-	ns
t <sub>d(off)</sub>	Turn-off-delay time	resistive load switching times"	-	40	-	ns
t <sub>f</sub>	Fall time	and Figure 18: "Switching time waveform")	-	20	-	ns

<sup>&</sup>lt;sup>(1)</sup>Defined by design, not subject to production test.

Table 8: Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Isp	Source-drain current		-		55	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		220	Α
V <sub>SD</sub> (2)	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 13 A	-		1.1	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 26 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	40		ns
Qrr	Reverse recovery charge	$V_{DD} = 25 V$ (see Figure 15: "Test circuit for	ı	5.6		nC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	2.8		Α

#### Notes:

<sup>&</sup>lt;sup>(1)</sup>Pulse width is limited by safe operating area.

 $<sup>^{(2)}\</sup>text{Pulse}$  test: pulse duration = 300  $\mu\text{s},$  duty cycle 1.5%

# 2.1 Electrical characteristics (curves)

Figure 2: Safe operating area GADG090320171546SOA  $\begin{array}{c|c} \textbf{I}_{\text{D}} & & & \\ \textbf{(A)} & \text{Operation in this area is} \\ \text{limited by } \textbf{R}_{\text{DS(on)}} \\ \end{array}$ t<sub>0</sub>=10 μs 10<sup>2</sup> t<sub>o</sub>=100 μs 10<sup>1</sup> t<sub>o</sub>=1 ms T<sub>.</sub>= 25°C 10<sup>0</sup> T,≤ 175 °C single pulse t<sub>p</sub>=10 ms 10<sup>-1</sup> 10° 10<sup>1</sup>  $\overline{V}_{DS}(V)$ 10<sup>-1</sup>

Figure 3: Thermal impedance GADG090320171546ZTH  $\delta = 0.5$  $\delta = 0.2$  $\delta = 0.1$ 10<sup>-1</sup>  $\delta = 0.05$  $\delta = 0.02$  $\delta = 0.01$  $Z_{th}=k^*R_{thj-c}$  $\delta=tp/T$ Single pulse 10<sup>-2</sup> 10<sup>-5</sup>  $\bar{t_p}$  (s) 10-4 10<sup>-3</sup> 10<sup>-2</sup> 10<sup>-1</sup>

Figure 4: Output characteristics

GIPD260120151445FSR

VGS= 7, 8, 9, 10 V

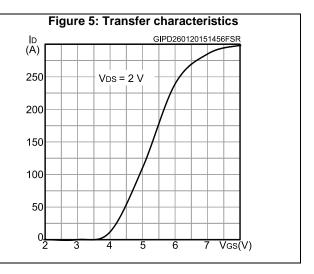
250

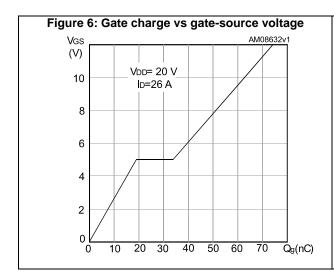
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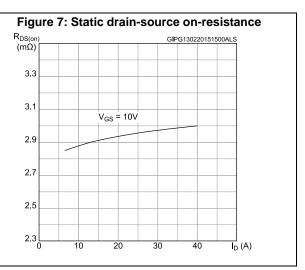
5V

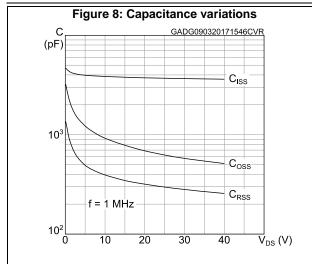
100

2 4 6 V<sub>DS</sub>(V)









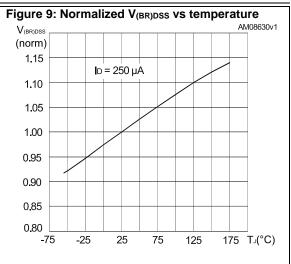
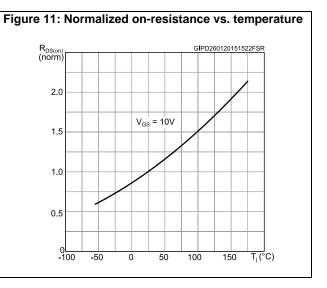
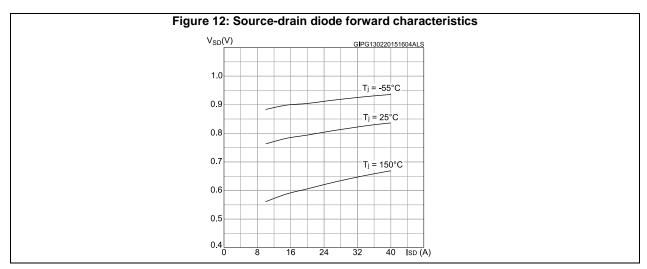


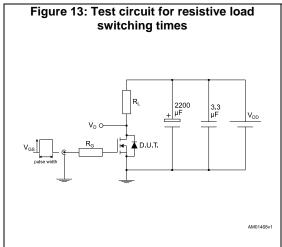
Figure 10: Normalized gate threshold voltage vs temperature AM08634v1  $V_{\text{GS(th)}}$ (norm) 1.2 1.0 8.0 ID = 250 μA 0.6 0.4 0.2 -75 -25 75 175 T<sub>J</sub>(°C) 25 125





Test circuits STL120N4F6AG

### 3 Test circuits



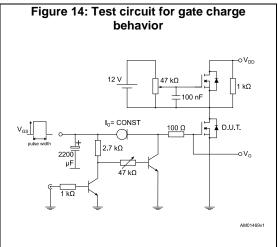
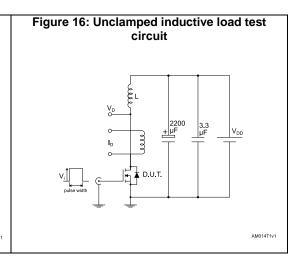
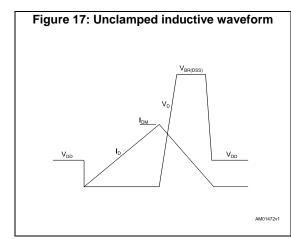
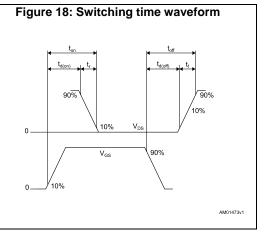


Figure 15: Test circuit for inductive load switching and diode recovery times







STL120N4F6AG Package information

#### **Package information** 4

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

#### PowerFLAT™ 5x6 WF type R package information 4.1

BOTTOM VIEW 5 E3 E3 Detail A Scale 3:1 62 0.08 L(x4) b(x8) D5(x4) D4 SIDE VIEW A Detail A ŏ A0Y5 8231817 R WF Rev 14

Figure 19: PowerFLAT™ 5x6 WF type R package outline

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Table 9: PowerFLAT™ 5x6 WF type R mechanical data

		mm	
Dim.	Min.	Тур.	Max.
А	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
С	5.80	6.00	6.10
D	5.00	5.20	5.40
D2	4.15		4.45
D3	4.05	4.20	4.35
D4	4.80	5.00	5.10
D5	0.25	0.4	0.55
D6	0.15	0.3	0.45
е		1.27	
Е	6.20	6.40	6.60
E2	3.50		3.70
E3	2.35		2.55
E4	0.40		0.60
E5	0.08		0.28
E6	0.20	0.325	0.45
E7	0.85	1.00	1.15
E9	4.00	4.20	4.40
E10	3.55	3.70	3.85
K	1.275		1.575
L	0.725	0.825	0.925
L1	0.175	0.275	0.375
θ	0°		12°

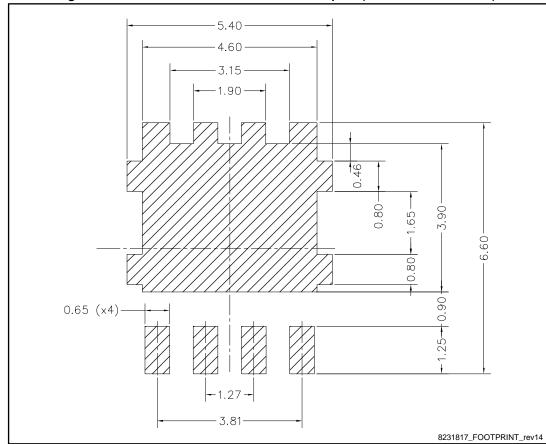


Figure 20: PowerFLAT™ 5x6 recommended footprint (dimensions are in mm)

Package information STL120N4F6AG

# 4.2 PowerFLAT™ 5x6 WF packing information

Figure 21: PowerFLAT™ 5x6 WF tape (dimensions are in mm)

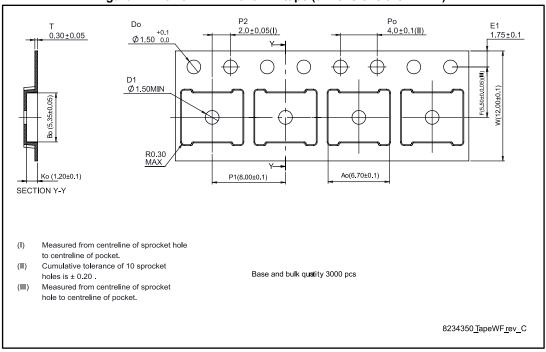
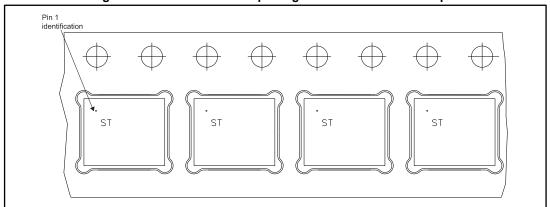


Figure 22: PowerFLAT™ 5x6 package orientation in carrier tape



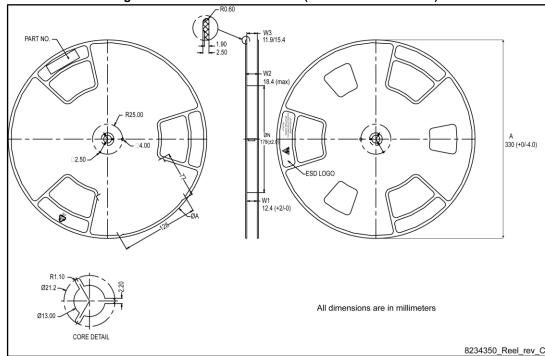


Figure 23: PowerFLAT™ 5x6 reel (dimensions are in mm)

Revision history STL120N4F6AG

# 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
19-Feb-2015	1	First release.
11-Apr-2016	2	Updated Table 2: "Absolute maximum ratings"
11 /\pi 2010		Minor text changes.
		Updated Table 2: "Absolute maximum ratings" and Table 8: "Source drain diode".
10-Jan-2017 3	3	Updated Figure 6: "Gate charge vs gate-source voltage" and Figure 8: "Capacitance variations".
		Minor text changes
		Updated Table 2: "Absolute maximum ratings" and Table 3: "Thermal data".
	-2017 4	Updated Figure 2: "Safe operating area", Figure 3: "Thermal
09-Mar-2017		impedance" and Figure 8: "Capacitance variations".
		Added Figure 9: "Normalized V(BR)DSS vs temperature" and Figure 10: "Normalized gate threshold voltage vs temperature".
		Minor text changes

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